

## SJ-FET

# TSF65R190S2/TSP65R190S2/TSA65R190S2/TSK65R190S2 650V N-Channel Super-Junction MOSFET Gen-II

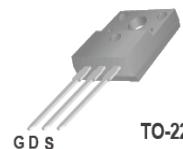
### Description

SJ-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance. This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy. SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.

### Features

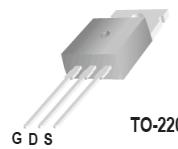
- Multi-Epi process SJ-FET
- 700V @ $T_J = 150^\circ\text{C}$
- Typ.  $R_{DS(on)} = 0.16\Omega$
- Ultra Low Gate Charge (typ.  $Q_g = 36.5\text{nC}$ )
- 100% avalanche tested

TSF65R190S2



TO-220F

TSP65R190S2



TO-220

TSA65R190S2

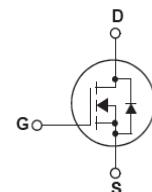


TO-3P

TSK65R190S2



TO-247



### Absolute Maximum Ratings

Symbol	Parameter	TSP_A_K65R190S2	TSF65R190S2	Unit
$V_{DSS}$	Drain-Source Voltage	650		V
$I_D$	Drain Current - Continuous ( $TC = 25^\circ\text{C}$ )	20*		A
	- Continuous ( $TC = 100^\circ\text{C}$ )	12.6*		
$I_{DM}$	Drain Current - Pulsed (Note 1)	65		A
$V_{GSS}$	Gate-Source voltage	$\pm 30$		V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	485		mJ
$I_{AS}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)	3.5		A
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	15		V/ns
$dVds/dt$	Drain Source voltage slope ( $V_{ds}=480\text{V}$ )	50		V/ns
$P_D$	Power Dissipation ( $TC = 25^\circ\text{C}$ )	150	34	W
$T_j, T_{STG}$	Operating and Storage Temperature Range	-55 to +150		°C
$T_L$	Maximum Lead Temperature for Soldering Purpose, $1/16''$ from Case for 10 Seconds	260		°C

\* Drain current limited by maximum junction temperature. Maximum duty cycle D=0.75.

### Thermal Characteristics

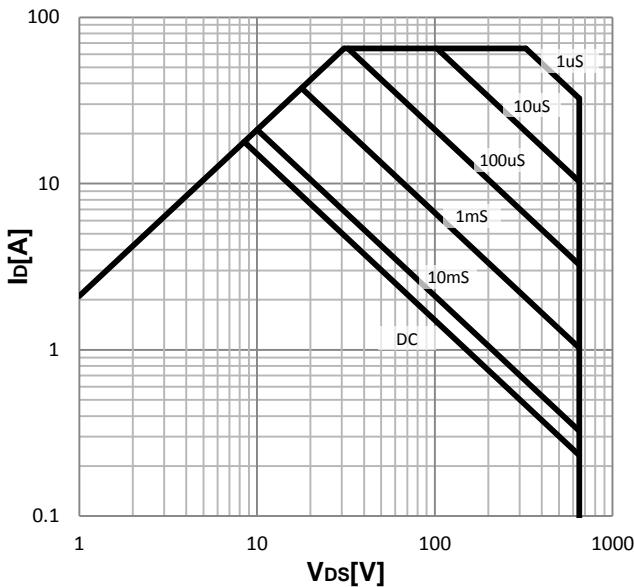
Symbol	Parameter	TSP_A_K65R190S2	TSF65R190S2	Unit
$R_{eJC}$	Thermal Resistance, Junction-to-Case	0.83	3.7	°C/W
$R_{eCS}$	Thermal Resistance, Case-to-Sink Typ.	0.5	-	°C/W
$R_{eJA}$	Thermal Resistance, Junction-to-Ambient	62	80	°C/W

<b>Symbol</b>	<b>Parameter</b>	<b>Conditions</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA, T <sub>J</sub> = 25°C	650	-	-	V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA, T <sub>J</sub> = 150°C	-	700	-	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250µA, Referenced to 25°C	-	0.6	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>D</sub> S = 650V, V <sub>G</sub> S = 0V -T <sub>C</sub> = 125°C	-	-	100	µA µA
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>G</sub> S = 30V, V <sub>D</sub> S = 0V	-	-	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>G</sub> S = -30V, V <sub>D</sub> S = 0V	-	-	-100	nA
<b>On Characteristics</b>						
V <sub>G</sub> S(th)	Gate Threshold Voltage	V <sub>D</sub> S = V <sub>G</sub> S, I <sub>D</sub> = 250µA	2.0	3.0	4.0	V
R <sub>D</sub> S(on)	Static Drain-Source On-Resistance	V <sub>G</sub> S = 10V, I <sub>D</sub> = 10A	-	-	0.19	Ω
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>D</sub> S = 100V, V <sub>G</sub> S = 0V, f = 1.0MHz	-	1505	-	pF
C <sub>oss</sub>	Output Capacitance		-	68	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	2.1	-	pF
Q <sub>g</sub>	Total Gate Charge	V <sub>D</sub> S = 480V, I <sub>D</sub> = 10A, V <sub>G</sub> S = 10V (Note 4)	-	36.5	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	8.7	-	nC
Q <sub>gd</sub>	Gate-Drain Charge		-	12.5	-	nC
R <sub>g</sub>	Gate resistance	f=1 MHz, open drain	-	9.8	-	Ω
<b>Switching Characteristics</b>						
t <sub>d</sub> (on)	Turn-On Delay Time	V <sub>D</sub> S = 400V, I <sub>D</sub> = 10A R <sub>G</sub> = 3.3Ω, V <sub>G</sub> S = 10V (Note 4)	-	38	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	39	-	ns
t <sub>d</sub> (off)	Turn-Off Delay Time		-	170	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	47	-	ns
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current	V <sub>G</sub> S = 0V, I <sub>S</sub> = 20A	-	-	20	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		-	-	65	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>G</sub> S = 0V, I <sub>S</sub> = 20A	-	0.9	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>G</sub> S = 0V, V <sub>D</sub> S = 400V, I <sub>S</sub> = 10A, dI <sub>F</sub> /dt = 100A/µs	-	318	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	5.5	-	µC
I <sub>rrm</sub>	Peak Reverse Recovery Current		-	24.9	-	A

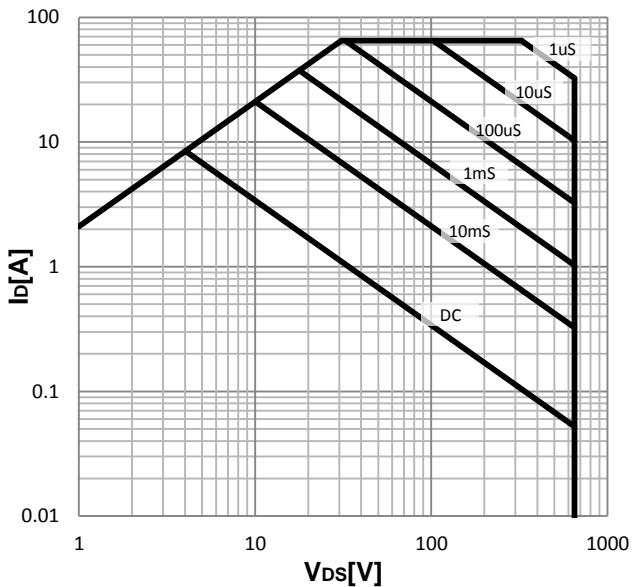
**NOTES:**

- Repetitive Rating: Pulse width limited by maximum junction temperature
- I<sub>D</sub>=I<sub>AS</sub>, V<sub>D</sub>D=50V, Starting T<sub>J</sub>=25 °C
- I<sub>SD</sub>≤I<sub>D</sub>, d<sub>i</sub>/d<sub>t</sub> ≤ 200A/us, V<sub>D</sub>D ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25 °C
- Essentially Independent of Operating Temperature Typical Characteristics

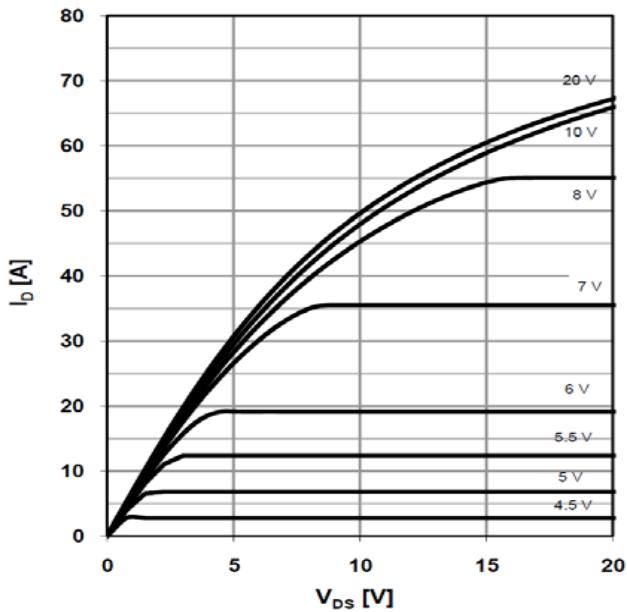
Safe operating area TC=25 °C  
parameter: tp; TO-220, TO-247



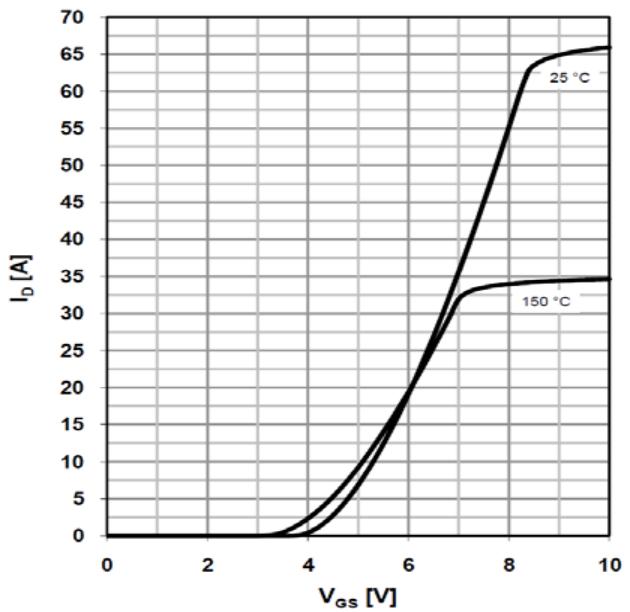
Safe operating area TC=25 °C  
parameter: tp; TO-220FullPAK



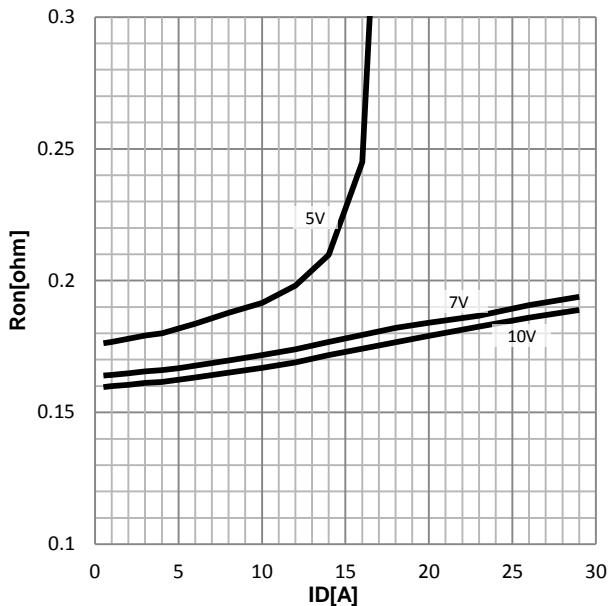
Typ. output characteristics  $T_f=25$  °C  
parameter:  $V_{GS}$



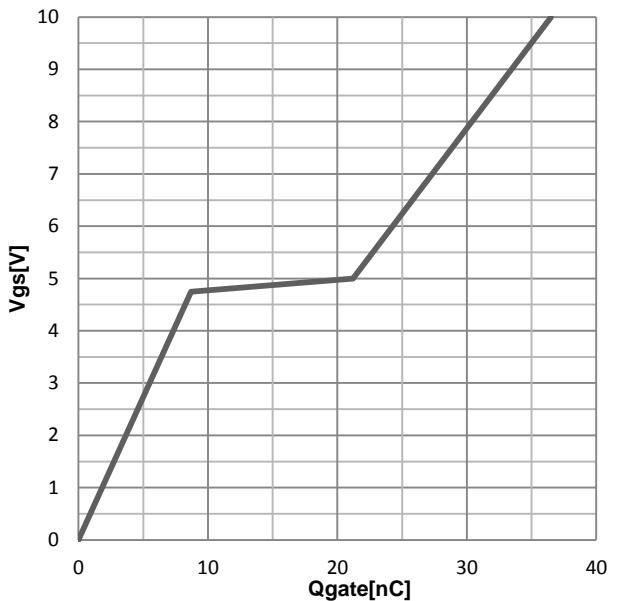
Typ. transfer characteristics



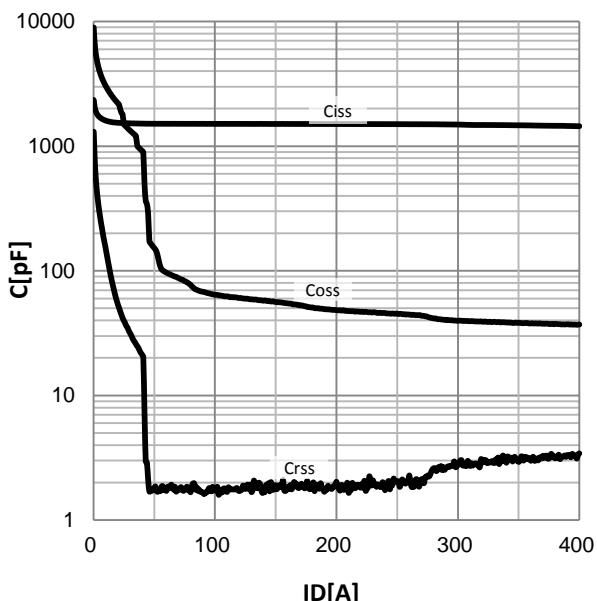
Typ. drain-source on-state resistance  
parameter :  $V_{GS}$



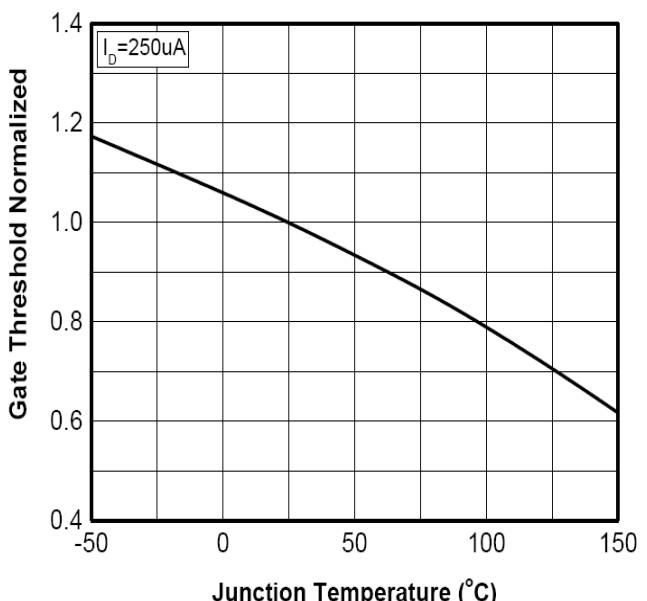
Typ. gate charge characteristics



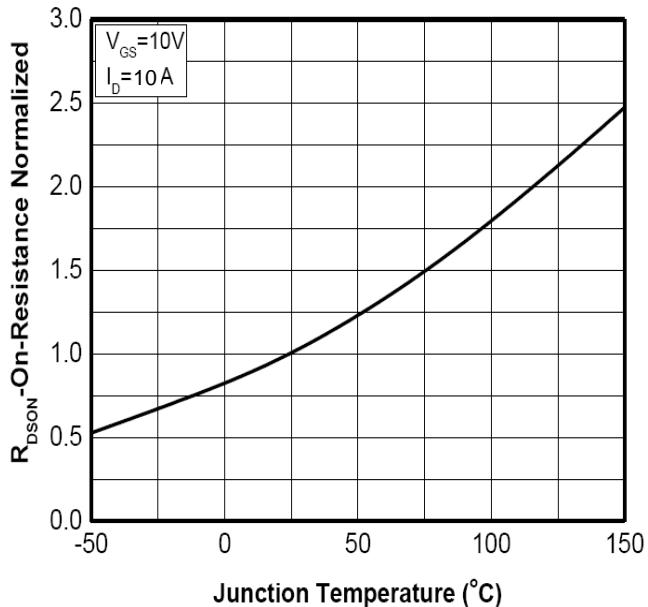
Typ. capacitances



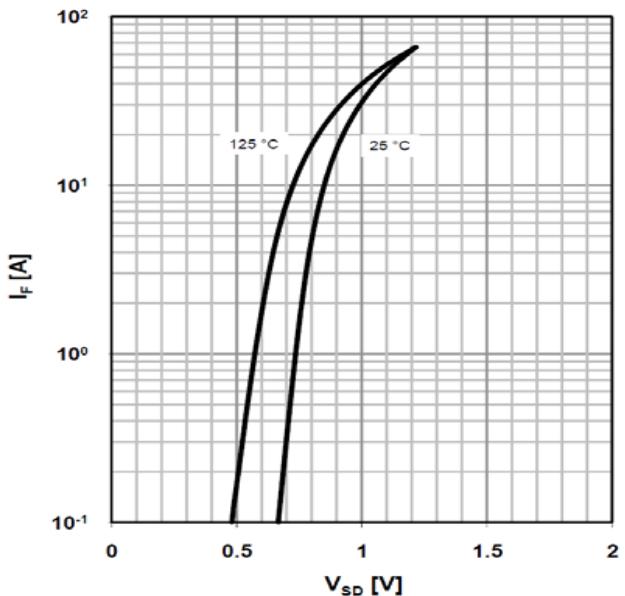
Normalized  $V_{GS(th)}$  characteristics



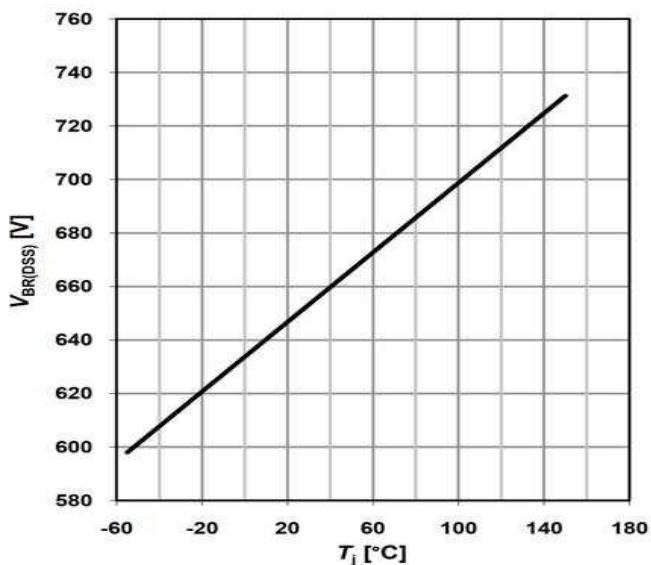
Normalized on resistance vs temperature



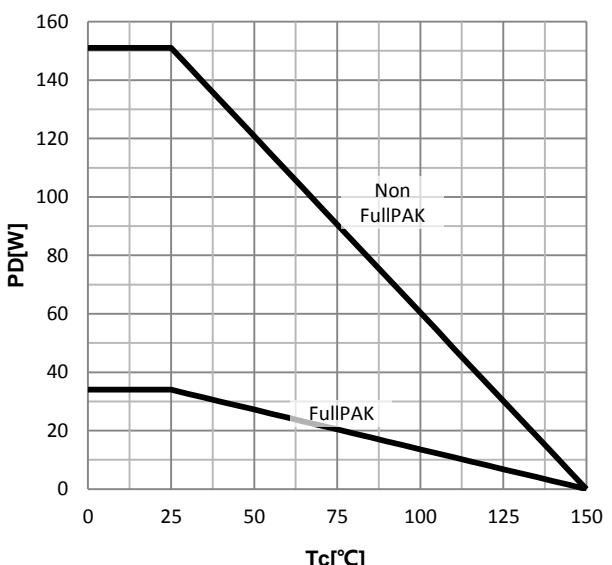
Forward characteristics of reverse diode



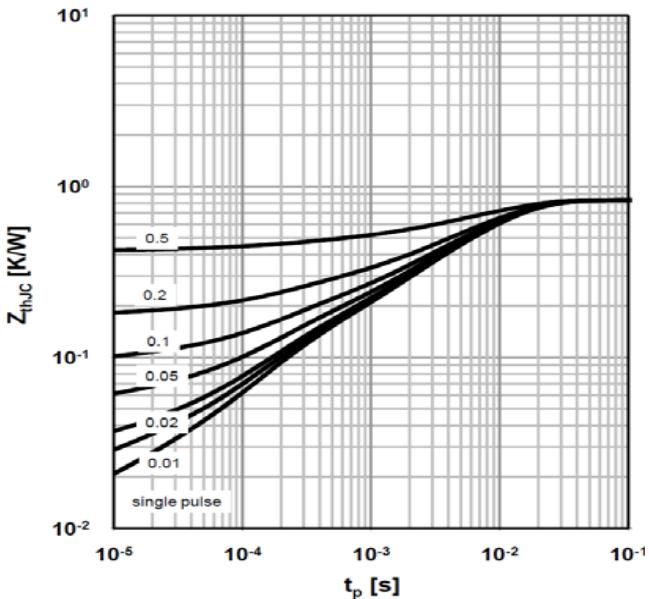
Drain-source breakdown voltage



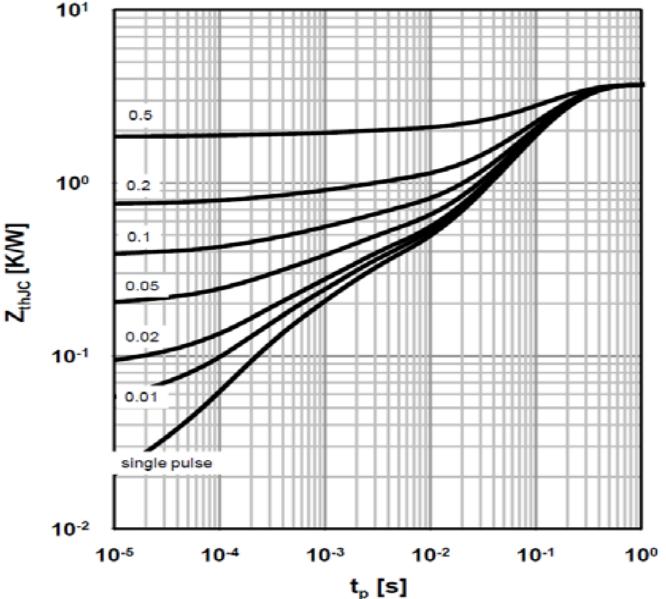
Power dissipation



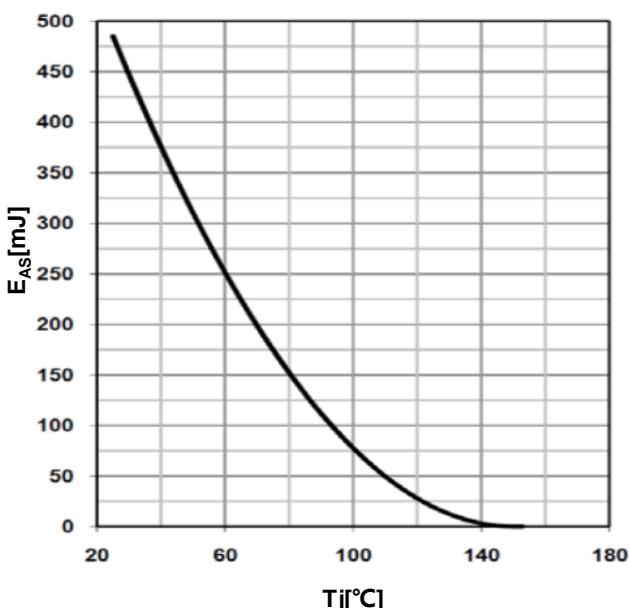
Max. transient thermal impedance parameter: D=tp/T; TO-220/3P/247

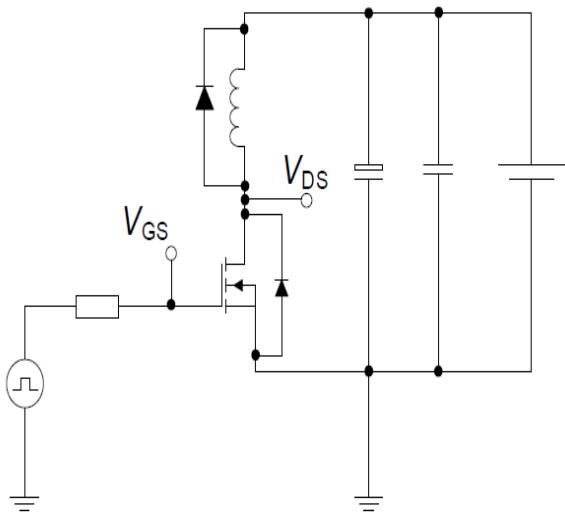
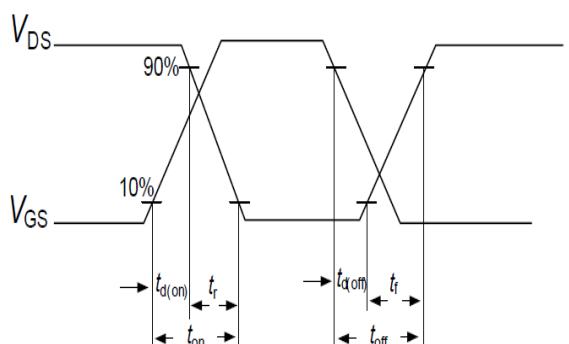
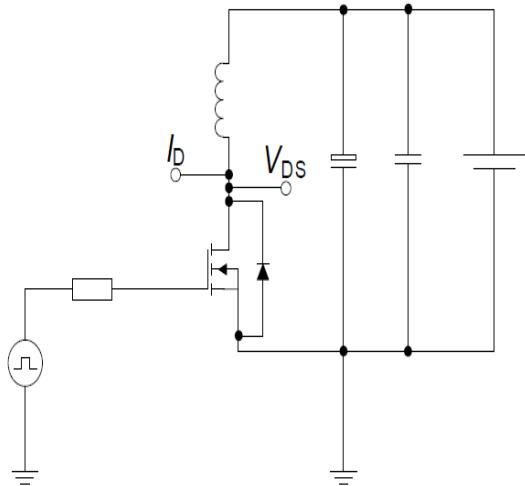
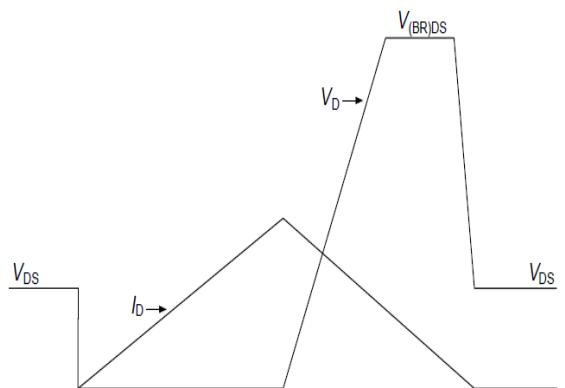


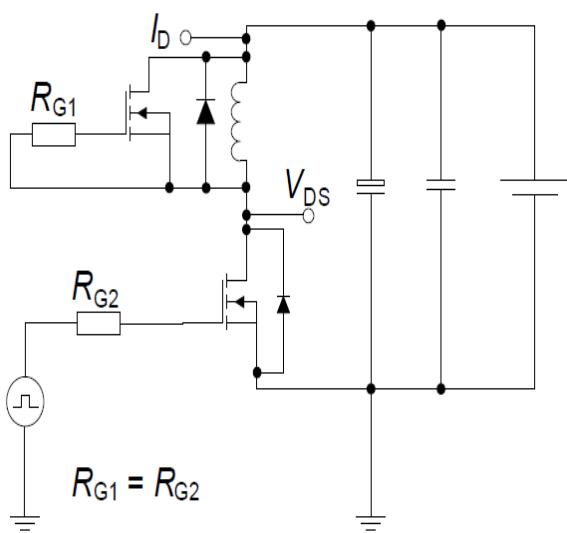
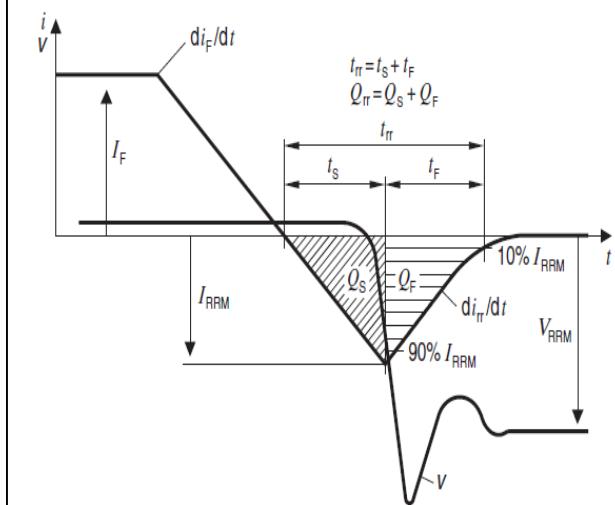
Max. transient thermal impedance parameter: D=tp/T; TO-220FullPAK



Avalanche energy



**Switching times test circuit and waveform for inductive load**
**Switching times test circuit for inductive load**

**Switching time waveform**

**Unclamped inductive load test circuit and waveform**
**Unclamped inductive load test circuit**

**Unclamped inductive waveform**


**Test circuit and waveform for diode characteristics**
**Test circuit for diode characteristics**

**Diode recovery waveform**




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